

## **Quarterly Reliability Monitoring Results**

## Quarters: Q1/2021 to Q4/2021

Based on structural similarity

Supplier Nexperia B.V. Name of Laboratory		User Part Number					
		BZB784-C12					
		Part Description					
		Nexperia DHAM	Zener				
Assembly reliability labs  Based on AEC-Q101 Test		SMD package					
		Test Conditions	Duration	# Lots	# Quantity	# Rejects	
	TEST						
	Pre- and Post-Stress						
# E1	Electrical Test	Tamb = 25 °C	N/A	see below	all parts	see below	
		JESD22-A113	241				
	PC	Bake Tamb = 125 °C Soak Tamb = 85 °C, RH = 85%	24 hours 168 hours				
# A1	Preconditioning	Reflow soldering	3 cycles	810	58300	0	
		MIL-STD-750-1	•			-	
	HTRB	M1038 Method A					
	High Temperature Reverse	Tj = Tjmax, Vr = 100% of max. datasheet					
# B1	Bias	reverse voltage	1000 hours	138	11040	0	
		MIL-STD-750-1					
		M1038 Method B					
" 541	SSOP	Tj = Tjmax, Iz = 100% of max. datasheet	10001	20	1600		
# B1b	Steady State Operational	reverse current	1000 hours	20	1600	0	
	тс	JESD22-A104					
# A4	Temperature Cycling	-65 °C to Timax, not to exceed 150°C	1000 cycles	170	13600	0	
# AT	,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,,	JESD22-A102	1000 cycles	170	13000		
	AC	Tamb = 121 °C, RH = 100 %					
# A3 alt	Autoclave	Pressure = 205 kPa (29.7 psia)	96 hours	170	13600	0	
	H3TRB	JESD22-A101					
	High Humidity High	Tamb = 85 °C, RH = 85%, VR = 80 % of					
# A2 alt	Temperature Reverse Bias	rated reverse voltage <sup>[1]</sup>	1000 hours	170	13600	0	
		MIL-STD-750 Method 1037					
<b>" ^ -</b>	IOL Intermittent Operating Life	ton = toff, devices powered to insure $\Delta Tj$ =	1000	170	12600	0	
# A5	intermittent Operating Life	100 C 101 13000 Cycles	1000 hours	170	13600	0	
	RSH	JESD22-A111					
# C8	Resistance to Solder Heat	260 °C ± 5 °C	10 s	130	3900	0	
	SD		10 3	130	3,00	<u> </u>	
# C10	Solderability	J-STD-002		363	3630	0	

<sup>[1]</sup> The maximum applied voltage is limited by test chamber set up and does not exceed 115V.

## **Calculation of FIT and MTTF**

Test considered for FIT calculation: High Temperature Reverse Bias (HTRB, Test #B1) Confidence level 60%, derated to 55 °C, activation energy 0.7 eV, test time 168 to 1000 hours

Wafer Fab	Technology	Quantity	Rejects	Failure Rate (FIT)	MTTF (hrs)
Nexperia					
DHAM	Zener	11040	0	0.38	2.60E+09

<sup>© 2022</sup> Nexperia B.V.

All information hereunder is per Nexperia's best knowledge. This document does not provide for any representation or warranty express or implied by Nexperia. In case Nexperia has tested the product, this documentation reflects the outcome of the analysis of the actually tested parts only.

nexperia.com